

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination MATSUI ET AL.	
		Examiner Helen Rossoshek	Art Unit 2825	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-6,175,946 B1	01-2001	Ly et al.	716/4
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	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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